IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Cann et al. Serial No.: 10/711,765

Filed: October 4, 2004

For: Inspection Methods and Structures for Visualizing and/or

Detecting Specific Chip Structures

Dkt. No.: **BUR920040035US1**

Conf. No.: **5764**Examiner: **Lee, H.**Art Unit: **2823**

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

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Sir:

Introductory Comments

In response to the Office Action dated September 13, 2006, Applicants respond as follows: